FPD Materials & Components and FPD Metrology

Japan Joint TC Chapter

Meeting Summary and Minutes

SEMI Standards Japan Winter Meetings

Friday, February 16, 2024
SEMI Japan/ Official Virtual TC Chapter Meeting (Hybrid)
15:00-18:20 [JST]

TC Chapter Announcements

Next TC Chapter Meeting:

FPD Materials & Components Japan TC Chapter and FPD Metrology Japan TC Chapter joint meeting will be held on Friday, June 21, 2024 14:00-17:00 via OVTCCM and at SEMI Japan, Tokyo, Japan.

Table 1 Meeting Attendees

Italics indicate virtual participants.

FPD Materials & Components TC Co-Chairs: Tadahiro Furukawa (Yamagata University), Ryoichi Watanabe (Japan Display), Toshimasa Eguchi (Sumitomo Bakelite)
FPD Metrology TC Co-Chairs: Ryoichi Watanabe (Japan Display), Akira Kawaguchi (Otsuka Electronics)
SEMI Staff: Akiko Yoshida (SEMI Japan)

Company	*Last*	*First*	*Company*	*Last*	*First*
FUJIFILM	*Ishizuka*	*Hiroshi*	*Sumitomo Bakelite*	*Eguchi*	*Toshimasa*
HOYA Corporation	*Kondo*	*Keitaro*	*SK-Electronics*	*Miyazaki*	*Shohei*
Japan Display	Ryoichi	Watanabe	Yamagata University	Furukawa	Tadahiro
Kei Techno Research	*Ochi*	*Keizo*	SEMI Japan	Sato	Hiroshi
Otsuka Electronics	*Kawaguchi*	*Akira*	SEMI Japan	Yoshida	Akiko
NIPPON STEEL Chemical & Material	Nakatsuka	Jun			

Table 2 Leadership Changes

WG/TF/SC/TC Name	*Previous Leader*	*New Leader*
FPD Materials & Components Japan TC Chapter		
None		
FPD Metrology Japan TC Chapter		
FPD Metrology Maintenance Task Force	--	Ryoichi Watanabe (Japan Display) Akira Kawaguchi (Otsuka Electronics) Tadahiro Furukawa (Yamagata Univ.)

Table 3 Committee Structure Changes

Previous WG/TF/SC Name	*New WG/TF/SC Name or Status Change*
FPD Materials & Components Japan TC Chapter	
None	

Table 3 Committee Structure Changes

Previous WG/TF/SC Name	*New WG/TF/SC Name or Status Change*
FPD Metrology Japan TC Chapter	
--	FPD Metrology Maintenance Task Force

Table 4 Ballot Results

Document #	*Document Title*	*Committee Action*
FPD Materials & Components Japan TC Chapter		
7157	Line Item Revision to SEMI D38-0723, GUIDE FOR QUALITY AREA OF FLAT PANEL DHISPLAY (FPD) MASKS	
Line Item 1	Correction of the Inequality Signs	**Passed**
FPD Metrology Japan TC Chapter		
None		

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 5 Activities Approved by the GCS between meetings of the TC Chapter

#	*Type*	*SC/TF/WG*	*Details*
FPD Materials & Components Japan TC Chapter			
None			
FPD Metrology Japan TC Chapter			
None			

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

#	*Type*	*SC/TF/WG*	*Details*
FPD Materials & Components Japan TC Chapter			
7215	SNARF	FPD Materials & Components Maintenance Task Force	Reapproval of SEMI D22-0818, Test Method for the Determination of Color, Transmittance of FPD Color Filter Assemblies
7216	SNARF	FPD Materials & Components Maintenance Task Force	Reapproval of SEMI D29-0519, Test Method for Heat Resistance in Flat Panel Display Color Filters
7217	SNARF	FPD Materials & Components Maintenance Task Force	Reapproval of SEMI D30-0519, Test Method for Light Resistance in Flat Panel Display Color Filters
7218	SNARF	Flexible Display Task Force	Reapproval of SEMI D66-0519, Terminology for Plastic Substrates of Flexible Display
7219	SNARF	FPD Materials & Components Maintenance Task Force	Reapproval of SEMI D67-0819, Test Method for Antifouling Property and Chemical Resistance of FPD Polarizing Films and Its Materials
FPD Metrology Japan TC Chapter			

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

#	*Type*	*SC/TF/WG*	*Details*
--	TFOF	FPD Metrology Maintenance Task Force	Newly formed.

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:
http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF

Table 7 Authorized Ballots

#	*When*	*TF*	*Details*
FPD Materials & Components Japan TC Chapter			
7215	Cycle 3-24	FPD Materials & Components Maintenance Task Force	Reapproval of SEMI D22-0818, Test Method for the Determination of Color, Transmittance of FPD Color Filter Assemblies
7216	Cycle 3-24	FPD Materials & Components Maintenance Task Force	Reapproval of SEMI D29-0519, Test Method for Heat Resistance in Flat Panel Display Color Filters
7217	Cycle 3-24	FPD Materials & Components Maintenance Task Force	Reapproval of SEMI D30-0519, Test Method for Light Resistance in Flat Panel Display Color Filters
7218	Cycle 3-24	Flexible Display Task Force	Reapproval of SEMI D66-0519, Terminology for Plastic Substrates of Flexible Display
7219	Cycle 3-24	FPD Materials & Components Maintenance Task Force	Reapproval of SEMI D67-0819, Test Method for Antifouling Property and Chemical Resistance of FPD Polarizing Films and Its Materials
FPD Metrology Japan TC Chapter			
None			

Table 8 SNARF(s) Granted a One-Year Extension

#	*TF*	*Title*	*Expiration Date*
FPD Materials & Components Japan TC Chapter			
None			
FPD Metrology Japan TC Chapter			
None			

Table 9 SNARF(s) Abolished

#	*TF*	*Title*
FPD Materials & Components Japan TC Chapter		
None		
FPD Metrology Japan TC Chapter		
None		

Table 10 Standard(s) to receive Inactive Status

Standard Designation	*Title*
FPD Materials & Components Japan TC Chapter	
None	
FPD Metrology Japan TC Chapter	
None	

Table 11 New Action Items

Item #	*Assigned to*	*Details*
FPD Materials & Components Japan TC Chapter		
FPDM&C_20240216_01	SEMI Staff	To forward the ballot adjudication result of Doc.#7157 to ISC A&R Subcommittee for procedural review.
FPDM&C_20240216_02	Each Task Force Co-leaders/ SEMI Staff	To create a Connect@SEMI site for the Task Forces under FPD Materials & Components Japan TC Chapter.
FPDM&C_20240216_03	FPD Materials & Components Maintenance Task Force	To review the documents for upcoming 5-year review.
FPDM&C_20240216_04	FPD Materials & Components Maintenance Task Force/ Flexible Display Task Force	To submit Reapproval ballots for SEMI D22, D29, D30, D66, and D67 for Cycle 3.
FPDM&C_20240216_05	FPD Mask Task Force	To send SNARF for New Standard, Specification of the Electrostatic Properties for FPD Photomasks and Blanks Package to FPD Materials & Components Global Technical Committee members for two weeks review.
FPD Metrology Japan TC Chapter		
FPDMet_20240216-1	FPD Metrology Maintenance Task Force	To submit SNARF for Revision to SEMI D31, Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection.
FPDMet_20240216-2	FPD Metrology Maintenance Task Force Co-Leaders/ SEMI Staff	To create a Connect@SEMI site for the FPD Metrology Maintenance Task Force.

Table 12 Previous Meeting Action Items

Item #	*Assigned to*	*Details*
FPD Materials & Components Japan TC Chapter		
FPDM&C_20231013_01	SEMI Staff	To forward the ballot adjudication results of Doc.#7105, 7106, 7107, and 7110 to ISC A&R Subcommittee for procedural review.→Closed
FPDM&C_20231013_02	FPD Mask Task Force	To submit Line Item Revision to SEMI D38-0723, GUIDE FOR QUALITY AREA OF FLAT PANEL DISPLAY (FPD) MASKS for Cycle 9.→Closed
FPDM&C_20231013_03	FPD Materials & Components Maintenance Task Force/ Flexible Display Task Force	To prepare 5 SNARFs by the next TC Chapter meeting.→Closed
FPD Metrology Japan TC Chapter		
FPDMet_06022023-1	Ryoichi Watanabe	The direction of the 5-year review of SEMI D31-0318 “Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection will be decided by the next committee meeting in October (Mr. Watanabe)→Closed

1 Welcome, Reminders, and Introductions

Tadahiro Furukawa called the meeting to order at 15:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: 01_Meeting Reminders

2 Review of Previous Meeting Minutes

The FPD Materials & Components Japan TC Chapter reviewed the minutes of the previous meeting.

Motion:	Approve the minutes for the previous FPD M&C Japan TC Chapter meeting with corrections.
By / 2nd:	By: Ryoichi Watanabe/ Japan Display Inc. Second: Jun Nakatsuka/ NIPPON STEEL Chemical & Material
Discussion:	None.
Vote:	6-Y 0-N. Motion Passed.

Attachment: 02_FPD M&C+FHE_JA _Mins_20231013_R1

The FPD Metrology Japan TC Chapter reviewed the minutes of the previous meeting.

Motion:	Approve the minutes for the previous FPD Metrology Japan TC Chapter meeting with one correction.
By / 2nd:	By: Ryoichi Watanabe/ Japan Display Inc. Second: Jun Nakatsuka/ NIPPON STEEL Chemical & Material
Discussion:	None.
Vote:	Result: 7-Y 0-N. Motion Passed.

Attachment: 03_FPD M&C+Met _JA _Mins_230602 v2.0

3 Liaison Reports

3.1 *FPD Metrology Korea TC Chapter*

Akiko Yoshida (SEMI Japan) reported for the FPD Metrology Korea TC Chapter. Of note:

- Automotive Display Task Force was newly formed at the previous meeting in September.
- The following three SNARFs and their ballot submission for Cycle 9, 2023 were approved by the GCS.
  - Doc.#7154, New Standard, Test Method for Flicker of Flat Panel Displays
  - Doc.#7155, Test Method for Optical Switchable Properties of Automotive Displays
  - Doc.#7156, Revision to SEMI D61-0723, Test Method of Perceptual Angle for OLED Displays
- Doc.#6975B, New Standard, Test Method for Response Time Evaluation of Displays with Variable Refresh Rate and Doc.#7156, Revision to SEMI D61-0723, Test Method of Perceptual Angle for OLED Displays were submitted for Cycle 9, 2023, but automatically failed as they didn't meet required 60% return rate.

Attachment: 04_Liaison report_FPDM_KR_Feb2024

3.2 *FPD Metrology Taiwan TC Chapter*

Akiko Yoshida (SEMI Japan) reported for the FPD Metrology Taiwan TC Chapter that that there had been no updates from the previous meeting.

Attachment: 05_FPD-M TW Liaison Report_2023may

4 SEMI Staff Report

Akiko Yoshida (SEMI Japan) gave the SEMI Staff Report. Of note:

- SEMI Standards meetings were held during SEMICON Japan 2023. As this year marks the 50th anniversary of SEMI Standards Program, it was celebrated at the Friendship Party. The panels introducing standards activities were also posted at the Standards 50th Anniversary Path in East Hall 4 at Exhibition site.
- The SEMI Standards Ballot Voting System will be upgraded to improve performance, security, and usability, by seamlessly connecting the SEMI Standards program membership database and SEMI Virtual Meeting (SVM) system. A new online ballot system was expected to be in full operation from Cycle 1, 2024, but it was postponed to Cycle 3.

Attachment: 06_Staff Report Dec 2023 HK_N_AY_20240216

5 Ballot Review

NOTE 1: TC Chapter adjudication of ballots is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment file name for each balloted document is provided.

5.1 *FPD Materials & Components Japan TC Chapter*

5.1.1 *Doc.#7157, Line Item Revision to SEMI D38-0723: GUIDE FOR QUALITY AREA OF FLAT PANEL DISPLAY (FPD) MASKS*

5.1.1.1 Line Item 1: Correction of the Inequality Signs

- Passed the TC Chapter review as balloted. Refer to attachment below for full details.

Attachment: 07_7157_Ballot report_D38-0723_Line Item Revision

5.2 *FPD Metrology Japan TC Chapter*

None.

6 Task Force Reports

6.1 *FPD Materials & Components Japan TC Chapter*

6.1.1 *Flexible Display Task Force*

No report was provided.

6.1.2 *FPD Mask Task Force*

Keitaro Kondo (HOYA Corporation) reported for the FPD Mask Task Force. Of note:

- The Task Force met on January 17, 2024 and discussed to develop new standard document about electrostatic property for case of FPD photomask and blanks.
- The Task Force has been preparing the draft of the new standard.
- The Task Force will prepare the SNARF to develop the new standard by the next TC meeting and ask ballot submission approval for Cycle 6.

Attachment: 08_240117 Minutes FPD_Mask_TF-2

6.1.3 *FPD Materials & Components Maintenance Task Force*

Hiroshi Ishizuka (FUJIFILM) reported for the FPD Materials & Components Maintenance Task Force in accordance with the file. The Task Force will propose SNARFs to reapprove the documents listed for 5-year review.

Attachment: 09_20240216Maintenance TF report

6.2 *FPD Metrology Japan TC Chapter*

None.

7 Old Business

7.1 *FPD Materials & Components Japan TC Chapter*

7.1.1 Project Period Review

None.

7.1.2 5-year Review

The following documents will be due for 5-year review. Reapproval SNARFs were proposed by the responsible Task Forces.

- SEMI D22-0818, Test Method for the Determination of Color, Transmittance of FPD Color Filter Assemblies

Motion:	Approve the SNARF for Reapproval of SEMI D22-0818, Test Method for the Determination of Color, Transmittance of FPD Color Filter Assemblies.
By / 2nd:	By: Toshimasa Eguchi/ Sumitomo Bakelite Second: Jun Nakatsuka/ NIPPON STEEL Chemical & Material
Discussion:	None.
Vote:	8-Y 0-N. Motion Passed.

Motion:	Authorize the Letter Ballot for Reapproval of SEMI D22-0818, Test Method for the Determination of Color, Transmittance of FPD Color Filter Assemblies for Cycle 3.
By / 2nd:	By: Toshimasa Eguchi/ Sumitomo Bakelite Second: Jun Nakatsuka/ NIPPON STEEL Chemical & Material
Discussion:	None.
Vote:	8-Y 0-N. Motion Passed.

Attachment: 10_SNARF_D22_Transmittance of FPD Color Filter

- SEMI D29-0519, Test Method for Heat Resistance in Flat Panel Display Color Filters

Motion:	Approve the SNARF for Reapproval of SEMI D29-0519, Test Method for Heat Resistance in Flat Panel Display Color Filters.
By / 2nd:	By: Toshimasa Eguchi/ Sumitomo Bakelite Second: Jun Nakatsuka/ NIPPON STEEL Chemical & Material
Discussion:	None.
Vote:	8-Y 0-N. Motion Passed.

Motion:	Authorize the Letter Ballot for Reapproval of SEMI D29-0519, Test Method for Heat Resistance in Flat Panel Display Color Filters for Cycle 3.
By / 2nd:	By: Toshimasa Eguchi/ Sumitomo Bakelite Second: Jun Nakatsuka/ NIPPON STEEL Chemical & Material
Discussion:	None.
Vote:	8-Y 0-N. Motion Passed.

Attachment: 11_SNARF_D29_Heat_Resistance

- SEMI D30-0519, Test Method for Light Resistance in Flat Panel Display Color Filters

Motion:	Approve the SNARF for Reapproval of SEMI D30-0519, Test Method for Light Resistance in Flat Panel Display Color Filters.
By / 2nd:	By: Toshimasa Eguchi/ Sumitomo Bakelite Second: Jun Nakatsuka/ NIPPON STEEL Chemical & Material
Discussion:	None.
Vote:	8-Y 0-N. Motion Passed.

Motion:	Authorize the Letter Ballot for Reapproval of SEMI D30-0519, Test Method for Light Resistance in Flat Panel Display Color Filters for Cycle 3.
By / 2nd:	By: Toshimasa Eguchi/ Sumitomo Bakelite Second: Jun Nakatsuka/ NIPPON STEEL Chemical & Material
Discussion:	None.
Vote:	8-Y 0-N. Motion Passed.

Attachment: 12_SNARF_D30_Light_Resistance

- SEMI D66-0519, Terminology for Plastic Substrates of Flexible Display

Motion:	Approve the SNARF for Reapproval of SEMI D66-0519, Terminology for Plastic Substrates of Flexible Display
By / 2nd:	By: Toshimasa Eguchi/ Sumitomo Bakelite Second: Ryoichi Watanabe/ Japan Display
Discussion:	None.
Vote:	8-Y 0-N. Motion Passed.

Motion:	Authorize the Letter Ballot for Reapproval of SEMI D66-0519, Terminology for Plastic Substrates of Flexible Display for Cycle 3.
By / 2nd:	By: Toshimasa Eguchi/ Sumitomo Bakelite Second: Ryoichi Watanabe/ Japan Display
Discussion:	None.
Vote:	8-Y 0-N. Motion Passed.

Attachment: 13_SNARF_D66_Terminology_for_Plastic_Substrates_of_Flexible_Display

- SEMI D67-0819, Test Method for Antifouling Property and Chemical Resistance of FPD Polarizing Films and Its Materials

Motion:	Approve the SNARF for Reapproval of SEMI D67-0819, Test Method for Antifouling Property and Chemical Resistance of FPD Polarizing Films and Its Materials
By / 2nd:	By: Hiroshi Ishizuka/ FUJIFILM Second: Ryoichi Watanabe/ Japan Display
Discussion:	None.
Vote:	7-Y 0-N. Motion Passed.

Motion:	Authorize the Letter Ballot for Reapproval of SEMI D66-0519, Terminology for Plastic Substrates of Flexible Display for Cycle 3.
By / 2nd:	By: Hiroshi Ishizuka/ FUJIFILM Second: Ryoichi Watanabe/ Japan Display
Discussion:	None.
Vote:	7-Y 0-N. Motion Passed.

Attachment: 14_SNARF_Reapproval of SEMI D67-0819_20240216

7.2 *FPD Metrology Japan TC Chapter*

7.2.1 *Project Period Review*

None.

7.2.2 *5-Year Reviews*

Ryoichi Watanabe (Japan Display) reported that SEMI D31-0318, Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection is due for 5-year review. He told he would propose forming a new Task Force to start revision activities as New Business.

8 New Business

8.1 *FPD Materials & Components Japan TC Chapter*

Furukawa Tadahiro (Yamagata University) told that the SEMI Standards Procedure Manual would be revised soon to include Connect@SEMI as the official platform for the Task Forces for communication. He recommended to have an explanatory session right before the next TC Chapter meeting.

8.2 *FPD Metrology Japan TC Chapter*

8.2.1 New TFOF

Ryoichi Watanabe (Japan Display) proposed a TFOF to form the FPD Metrology Maintenance Task Force to address 5-year review documents as well as to review the proposed documents of the global FPD Metrology TC Chapter.

Motion:	Approve the TFOF for forming FPD Metrology Maintenance Task Force.
By / 2nd:	By: Akira Kawaguchi/ Otsuka Electronics Second: Tadahiro Furukawa/ Yamagata University
Discussion:	None.
Vote:	7-Y 0-N. Motion Passed.

The committee also reviewed draft SNARF for Line Item Revision to SEMI D31. However, the revision work includes a change in “Scope” section of SEMI D31, which is considered to be a “major revision,” it was recommended by the committee to change the SNARF from “Line Item Revision” to “Revision” and propose it at the next FPD Metrology Japan TC Chapter meeting.

Attachment: 15_TFOF_Metrolgy-newTF

9 Action Item Review

9.1 *Open Action Items*

Item #	*Assigned to*	*Details*
FPD Materials & Components Japan TC Chapter		
FPDM&C_20231013_01	SEMI Staff	To forward the ballot adjudication results of Doc.#7105, 7106, 7107, and 7110 to ISC A&R Subcommittee for procedural review.→Closed
FPDM&C_20231013_02	FPD Mask Task Force	To submit Line Item Revision to SEMI D38-0723, GUIDE FOR QUALITY AREA OF FLAT PANEL DISPLAY (FPD) MASKS for Cycle 9.→Closed
FPDM&C_20231013_03	FPD Materials & Components Maintenance Task Force/ Flexible Display Task Force	To prepare 5 SNARFs by the next TC Chapter meeting.→Closed
FPD Metrology Japan TC Chapter		
FPDMet_06022023-1	Ryoichi Watanabe	The direction of the 5-year review of SEMI D31-0318 “Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection will be decided by the next committee meeting in October (Mr. Watanabe).→Closed.

9.2 *New Action Items*

Item #	*Assigned to*	*Details*
FPD Materials & Components Japan TC Chapter		
FPDM&C_20240216_01	SEMI Staff	To forward the ballot adjudication result of Doc.#7157 to ISC A&R Subcommittee for procedural review.
FPDM&C_20240216_02	Each Task Force Co-leaders/ SEMI Staff	To create a Connect@SEMI site for the Task Forces under FPD Materials & Components Japan TC Chapter.
FPDM&C_20240216_03	FPD Materials & Components Maintenance Task Force	To review the documents for upcoming 5-year review.
FPDM&C_20240216_04	FPD Materials & Components Maintenance Task Force/ Flexible Display Task Force	To send Reapproval ballots for SEMI D22, D29, D30, D66, and D67 for Cycle 3.
FPDM&C_20240216_05	FPD Mask Task Force	To submit SNARF for New Standard, Specification of the Electrostatic Properties for FPD Photomasks and Blanks Package to FPD Materials & Components Global Technical Committee members for two weeks review.
FPD Metrology Japan TC Chapter		
FPDMet_20240216-1	FPD Metrology Maintenance Task Force	To submit SNARF for Revision to SEMI D31, Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection.
FPDMet_20240216-2	FPD Metrology Maintenance Task Force Co-Leaders/ SEMI Staff	To create a Connect@SEMI site for the FPD Metrology Maintenance Task Force.

10 Next Meeting and Adjournment

- FPD Materials & Components Japan TC Chapter and FPD Metrology Japan TC Chapter joint meeting will be held on Friday, June 21, 2024 14:00-17:00 via OVTCCM and at SEMI Japan, Tokyo, Japan.

See http://www.semi.org/standards-events for the current list of events.

Adjournment: [18:20].

Respectfully submitted by:

Akiko Yoshida

Standards & EHS

SEMI Japan

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Email: ayoshida@semi.org

Minutes tentatively approved by:

FPD Materials & Components Japan TC Chapter	
Tadahiro Furukawa (Yamagata University), Co-chair	March 1, 2024
Ryoichi Watanabe (Japan Display, Co-chair	March 1, 2024
Toshimasa Eguchi (Sumitomo Bakelite), Co-chair	March 1, 2024
FPD Metology Japan TC Chapter	
Ryoichi Watanabe (Japan Display, Co-chair	March 1, 2024
Akira Kawaguchi (Otsuka Electronics), Co-chair	March 1, 2024

Table 13 Index of Available Attachments[#1]

Title	*Title*
01_Meeting Reminders	09_20240216Maintenance TF report
02_FPD M&C+FHE_JA _Mins_20231013_R1	10_SNARF_D22_Transmittance of FPD Color Filter
03_FPD M&C+Met _JA _Mins_230602 v2.0	11_SNARF_D29_Heat_Resistance
04_Liaison report_FPDM_KR_Feb2024	12_SNARF_D30_Light_Resistance
05_FPD-M TW Liaison Report_2023may	13_SNARF_D66_Terminology_for_Plastic_Substrates_of_Flexible_Display
06_Staff Report Dec 2023 HK_N_AY_20240216	14_SNARF_Reapproval of SEMI D67-0819_20240216
07_7157_Ballot report_D38-0723_Line Item Revision	15_TFOF_Metrolgy-newTF
08_240117 Minutes FPD_Mask_TF-2	

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Akiko Yoshida at the contact information above.